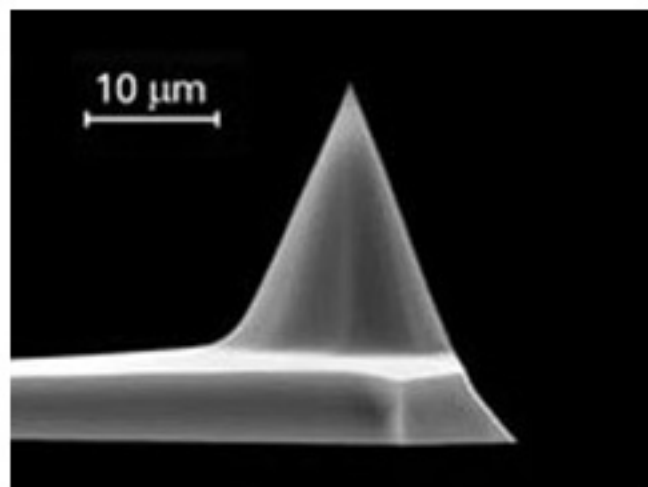


CSC11

PROBE



SEM image of uncoated silicon SPM probe tip

Silicon etched probe tip of the CSC series has a conical shape.

Typical probe tip radius of uncoated tip
10 nm

Full tip cone angle*
40°

Tip aspect ratio
more than 3:1 (4:1 typical)

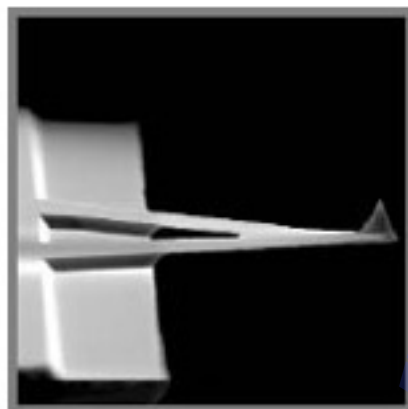
Total tip height
20..25 μm

Probe material
n-type silicon (phosphorus doped)

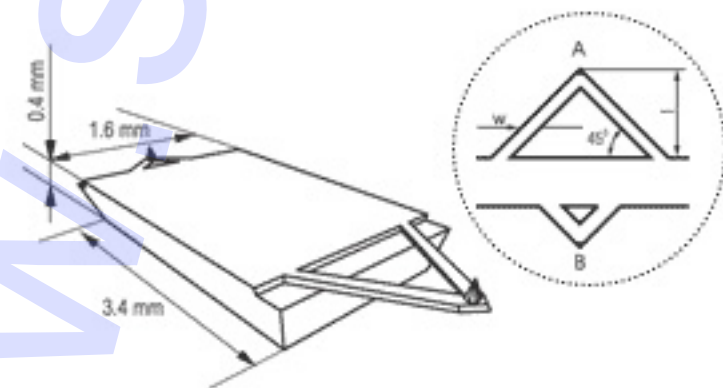
Probe bulk resistivity
0.01..0.05 Ohm*cm

*The full cone angle may be less than 40° at the last 200 nm of the tip end.

CANTILEVERS



SEM image of triangular cantilever of the CSC11 series.



Schematic drawing of the probe chip.

CSC11 Cantilevers	Resonant Frequency, kHz			Spring Constant, N/m			Length l ± 5, μm	Width w ± 3, μm	Thickness t ± 0.3, μm
	min	typ	max	min	typ	max			
A	20	28	40	0.1	0.35	0.9	200	40	1.0
B	100	155	235	1.5	6.0	16.5	90		



MikroMasch中国代理：
本原纳米仪器有限公司
Tel: 800-830-3560